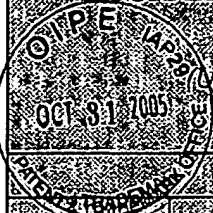
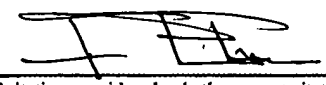
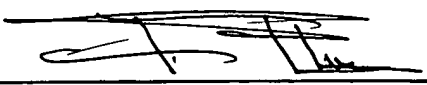
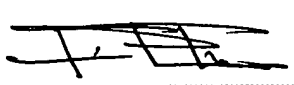


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				David G. MARROW et al.			
				FILING DATE		GROUP	
				12/09/2003		2857 2877	
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EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
fc	AA	3,725,378	04/03/1973	Chamberlin	—	—	
fc	AB	3,779,712	12/18/1973	Calvert et al.	—	—	
fc	AC	4,175,169	11/20/1979	Beals et al.	—	—	
fc	AD	4,182,810	01/08/1980	Willcox	—	—	
fc	AE	4,243,619	01/06/1981	Fraser et al.	—	—	
fc	AF	4,469,853	09/04/1984	Mori	—	—	
fc	AG	4,543,399	09/24/1985	Jenkins, III et al.	—	—	
fc	AH	4,588,790	05/13/1986	Jenkins, III et al.	—	—	
fc	AI	4,621,952	11/11/1986	Aronson	—	—	
fc	AJ	4,888,704	12/19/1989	Topliss et al.	—	—	
fc	AK	5,096,634	03/17/1992	Tsadares et al.	—	—	
fc	AL	5,121,337	06/09/1992	Brown	—	—	
fc	AM	5,202,395	04/13/1993	Chambon	—	—	
fc	AN	5,274,056	12/28/1993	McDaniel et al.	—	—	
fc	AO	5,352,749	10/04/1994	DeChellis et al.	—	—	
fc	AP	5,405,922	04/11/1995	DeChellis et al.	—	—	
fc	AQ	5,436,304	07/25/1995	Griffin et al.	—	—	
fc	AR	5,462,999	10/31/1995	Griffin et al.	—	—	
fc	AS	5,589,555	12/31/1996	Zboril et al.	—	—	
fc	AT	5,638,172	06/10/1997	Alsmeyer et al.	—	—	
fc	AU	5,675,253	10/07/1997	Smith et al.	—	—	
fc	AV	5,678,751	10/21/1997	Buchanan et al.	—	—	
fc	AW	5,682,309	10/28/1997	Bartusiak et al.	—	—	
fc	AX	5,696,213	12/09/1997	Schiffino et al.	—	—	
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				11-2005			
<p>*EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next comment to applicant</p>							

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				David G. MARROW et al.				
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fil	AA	6,072,576	06/06/2000	McDonald et al.	—	—		
fil	AB	6,204,664	03/20/2001	Sardashti et al.	—	—		
fil	AC	6,218,484	04/17/2001	Brown et al.	—	—		
fil	AD	6,405,579	06/18/2002	Tjahjadi et al.	—	—		
fil	AE	6,673,878	01/06/2004	Donck	—	—		
fil	AF	2004/0233425	11/25/2004	Long et al.	—	—		
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							YES	NO
fil	AG	EP 238 796	30.09.87	Europe	—	—		
fil	AH	EP 406 805	13.12.95	Europe	—	—		
fil	AI	JP 02038841	1990.02.08	Japan (w/Abstract)	—	—		
fil	AJ	WO 94/21962	29.09.94	PCT	—	—		
fil	AK	WO 96/41822	27.12.96	PCT	—	—		
fil	AL	WO 99/01750	14.01.99	PCT	—	—		
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fil	AM	K.R. Beebe et al., "An Introduction to Multivariate Calibration and Analysis," Analytical Chemistry, Vol. 59, No. 17, pp. 1007A-1017A, Sept. 1, 1987.						
fil	AN	J. M. Tedesco et al., "Calibration of dispersive Raman Process Analyzers," The Society Of Photo-Optical Instrumentation Engineers, Vol. 3537, pp. 200-212, 1999.						
fil	AO	G.A. Bakken et al., "Examination of Criteria for Local Model Principal Component Regression," Society for Applied Spectroscopy, Vol. 51, No. 12, pp. 1814-1822, 1997.						
fil	AP	P. Erlich et al., "Fundamentals of the Free-Radical Polymerization of Ethylene," Advanced Polymer Science, Vol. 7, pp. 386-448, 1970.						
fil	AQ	M.L. Myrick et al., "In Situ Fiber-Optic Raman Spectroscopy of Organic Chemistry in a Supercritical Water Reactor," Journal of Raman Spectroscopy, Vol. 25, pp. 59-65, 1994.						
fil	AR	T. Naes et al., "Locally Weighted Regression and Scatter Correction for Near-Infrared Reflectance Data," Analytical Chemistry, Vol. 62, pp. 664-673, 1990.						
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<p>* EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609. Draw line though citation if not in conformance and not considered. Include copy of this form with next comment to applicant</p>								

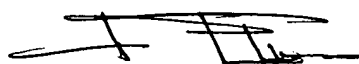
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		2003B001/2	10/731,708
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		David G. MARROW et al.	
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file	AA	J.J. Zacca et al., "Modelling of the Liquid Phase Polymerization of Olefins in Loop reactors." Chemical Engineering Science, Vol. 48, No. 22, pp. 3743-3765, 1993.	
file	AB	L.P. Russo et al., "Moving-Horizon State Estimation Applied to an Industrial Polymereization Process," American Control Conf. Proc., San Diego, CA, 1999.	
file	AC	H. Martens et al., "Multivariate Calibration," Wiley & Sons Ltd., pp. viii-ix, 1989.	
file	AD	Multivariate Data Analysis for Windows - Version 3.0, excerpted from Pirouette Software Manual, Exploratory Analysis: Principal Component Analysis, pp. 5-13 through 5-40, 1985-2000.	
file	AE	E.P.C. Lai et al., "Noninvasive Spectroscopic Detection of Bulk Polymerization by Stimulated Raman Scattering," Applied Spectroscopy, Vol. 48, No. 8, 1994.	
file	AF	S. Sekulic et al., "Nonlinear Multivariate Calibration Methods in Analytical Chemistry," Analytical Chemistry, Vol 65, No. 19, pp. 835A-845A, Oct. 1, 1993.	
file	AG	E.D. Lipp et al., "On-Line Monitoring Of Chlorosilane Streams By Raman Spectroscopy," Reprinted from Applied Spectroscopy, Vol 52, No. 1, January, 1998.	
file	AH	D.R. Battiste et al., "On-Line Raman Analysis of Ethylene and Hexene in the Phillips 1-Hexene and Polyethylene Processes," Gulf Coast Conference presentation (Abstract)	
file	AI	M.J. Pelletier et al.; "Optical fibers enable Raman instruments to analyze industrial process problems quickly and accurately." Raman Spectroscopy—Keeps Industry Under Control, Reprint: Photonics Spectra, 4 pgs., October, 1997.	
file	AJ	V. Centner et al., "Optimization in Locally Weighted Regression," Analytical Chemistry, Vol. 70, No. 19, pp. 4206-4211, Oct. 1, 1998.	
file	AK	"Principal Components Analysis," excerpted from PLS_Toolbox, Version 2.0 Data Analysis Manual, Eigenvector Research, Inc., pp. 32-34, 1998.	
file	AL	L. Markwort et al., "Raman Imaging of Heterogeneous Polymers: A Comparison of Global versus Point Illumination," Applied Spectroscopy, Vol. 49, No. 10, pp. 1411-1430, 1995.	
file	AM	I. Modric et al., "Raman- und Infrarotspektren isotaktischer Polyalkylathylene*," Colloid & Polymer Sci., Vol. 254, pp. 342-347, 1976.	
file	AN	M.G. Hansen et al., "Real-Time Monitoring of Industrial Polymers," Raman Review; pp. 1-4, 3/98.	
file	AO	S.E. Nave "Rugged Fiber Optic Probes and Sampling Systems for Remote Chemical Analysis Via the Raman Technique," ISA, Paper #96-042, pp. 453-467, 1996.	
file	AP	M.J. Pelletier et al., "Shining a Light on Wet Process Control," Semiconductor International, 4 pages, March, 1996.	
file	AQ	K.P.J. Williams et al., "Use of Micro Raman Spectroscopy for the Quantitative Determination of Polyethylene Density Using Partial Least-Squares Calibration," Journal of Raman Spectroscopy, Vol. 26, pp. 427-433, 1995.	
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INFORMATION DISCLOSURE STATEMENT <i>(Use several sheets if necessary)</i>				ATTY. DOCKET NO.		SERIAL NO.	
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December 9, 2003		Unassigned 2877					

U.S. PATENT DOCUMENTS							
*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
RE	AA	4,620,049	10/28/86	Schmidt et al.	585	501	
RE	AB	5,151,474	09/29/92	Lange et al.	526	60	
RE	AC	5,270,274	12/14/93	Hashiguchi et al.	502	115	
RE	AD	5,892,228	04/06/99	Cooper et al.	250	339.12	
WB	AE	5,999,255	12/07/99	Dupée et al.	356	301	
WB	AF	6,144,897	11/07/00	Selliers	700	269	
RE	AG	6,479,597 B1	11/12/02	Long et al.	526	59	
	AH						
	AI						
	AJ						
	AK						

FOREIGN PATENT DOCUMENTS								
		DOCUMENT NUMBER	PUBL. DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
RE	AL	EP0561078 B1	04/23/97	Europe	C08F	2/00		X
RE	AM	WO 01/09201	02/08/01	PCT	C08F	10/00		X
RE	AN	WO 01/09203	02/08/01	PCT	C08F	10/00		X
RE	AO	WO 98/08066	02/26/98	PCT	G01J	3/44		X

OTHER DISCLOSURES (Including Author, Title, Date, Pertinent Pages of Publication, Etc.)		
	AP	Ardell, George G., et al., Model Prediction for Reactor Control," Chemical Engineering Progress, American Institute of Chemical Engineers, vol. 79, no. 6, pp. 77-83 (June 1, 1983).
	AQ	

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